ON Semiconductor

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MOSFET – Power, Single, N-Channel, μ8FL 30 V, 44 A

Features

- Low R_{DS(on)} to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

Applications

- DC-DC Converters
- Power Load Switch
- Notebook Battery Management

MAXIMUM RATINGS (T_J = 25°C unless otherwise stated)

Paran	Symbol	Value	Unit		
Drain-to-Source Voltage	V_{DSS}	30	V		
Gate-to-Source Voltage			V_{GS}	±20	V
Continuous Drain		T _A = 25°C	I _D	13.3	Α
Current R _{θJA} (Note 1)		T _A = 80°C	1	9.9	
Power Dissipation $R_{\theta JA}$ (Note 1)		T _A = 25°C	P _D	2.09	W
Continuous Drain		T _A = 25°C	I _D	18.2	Α
Current $R_{\theta JA} \le 10 \text{ s}$ (Note 1)		T _A = 80°C		13.6	
Power Dissipation $R_{\theta JA} \le 10 \text{ s (Note 1)}$	Steady	T _A = 25°C	P _D	3.9	W
Continuous Drain	State	T _A = 25°C	Ι _D	8.2	Α
Current R _{θJA} (Note 2)		T _A = 80°C	1	6.1	
Power Dissipation $R_{\theta JA}$ (Note 2)		T _A = 25°C	P _D	0.79	W
Continuous Drain		T _C = 25°C	Ι _D	44	Α
Current R _{θJC} (Note 1)		T _C = 80°C	1	33	
Power Dissipation $R_{\theta JC}$ (Note 1)		T _C = 25°C	P _D	23.6	W
Pulsed Drain Current	T _A = 25°0	C, t _p = 10 μs	I _{DM}	128	Α
Operating Junction and S	T _J , T _{stg}	–55 to +150	°C		
Source Current (Body Die	I _S	20	Α		
Drain to Source dV/dt	dV/dt	6.0	V/ns		
Single Pulse Drain-to-So $(T_J=25^{\circ}C,V_{DD}=50V,V_{DD}=50V,V_{DD}=0.1$ mH, $R_G=25\Omega)$	E _{AS}	31	mJ		
Lead Temperature for So (1/8" from case for 10 s)	TL	260	°C		

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.

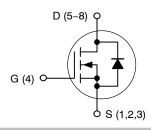


ON Semiconductor®

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V _{(BR)DSS} R _{DS(on)} MAX		I _D MAX
30 V	7.4 mΩ @ 10 V	44 A
	11 mΩ @ 4.5 V	447

N-Channel MOSFET





WDFN8 (μ8FL) CASE 511AB



4C10 = Specific Device Code A = Assembly Location Y = Year

WW = Work Week ■ Pb–Free Package

(Note: Microdot may be in either location)

ORDERING INFORMATION

Device	Package	Shipping [†]
NTTFS4C10NTAG	WDFN8 (Pb-Free)	1500 / Tape & Reel
NTTFS4C10NTWG	WDFN8 (Pb-Free)	5000 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

- 2. Surface-mounted on FR4 board using the minimum recommended pad size.
- 3. This is the absolute maximum ratings. Parts are 100% tested at $T_J = 25^{\circ}C$, $V_{GS} = 10 \text{ V}$, $I_L = 17 \text{ A}$, $E_{AS} = 14 \text{ mJ}$.

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain)	$R_{ heta JC}$	5.3	
Junction-to-Ambient - Steady State (Note 4)	$R_{ heta JA}$	59.9	°C/W
Junction-to-Ambient - Steady State (Note 5)	$R_{ heta JA}$	157.8	°C/VV
Junction-to-Ambient - (t ≤ 10 s) (Note 4)	$R_{ heta JA}$	31.8	

- 4. Surface–mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
- 5. Surface-mounted on FR4 board using the minimum recommended pad size.

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS							
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		30			V
Drain-to-Source Breakdown Voltage (transient)	V _{(BR)DSSt}	V_{GS} = 0 V, $I_{D(aval)}$ = 7.1 A, T_{case} = 25°C, $t_{transient}$ = 100 ns		34			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} / T _J				14.5		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	$V_{GS} = 0 \text{ V}, \qquad T_{J} = 25^{\circ}\text{C}$				1.0	
		V _{DS} = 24 V	T _J = 125°C			10	μΑ
Gate-to-Source Leakage Current	I _{GSS}	$V_{DS} = 0 V, V_{GS}$	= ±20 V			±100	nA
ON CHARACTERISTICS (Note 6)							
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_D = 250 \mu A$		1.3		2.2	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J				4.5		mV/°C
Drain-to-Source On Resistance	in-to-Source On Resistance $R_{DS(on)}$ $V_{GS} = 10 \text{ V}$ $I_D =$		I _D = 30 A		5.9	7.4	
		V _{GS} = 4.5 V	I _D = 15 A		8.8	11	mΩ
Forward Transconductance	9FS	V _{DS} = 1.5 V, I _D = 15 A			43		S
Gate Resistance	R_{G}	T _A = 25°C			1.0		Ω
CHARGES AND CAPACITANCES							
Input Capacitance	C _{ISS}				993		
Output Capacitance	C _{OSS}	V _{GS} = 0 V, f = 1 MH:	z, V _{DS} = 15 V		574		pF
Reverse Transfer Capacitance	C _{RSS}				163		
Capacitance Ratio	C _{RSS} /C _{ISS}	V _{GS} = 0 V, V _{DS} = 15 V, f = 1 MHz			0.164		
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 4.5 V, V _{DS} = 15 V; I _D = 30 A			9.7		
Threshold Gate Charge	Q _{G(TH)}				1.5		
Gate-to-Source Charge	Q _{GS}				2.8		nC
Gate-to-Drain Charge	Q_{GD}				4.8		
Gate Plateau Voltage	V _{GP}				3.2		V
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 10 V, V _{DS} = 1		18.6		nC	

SWITCHING CHARACTERISTICS (Note 7)

- 6. Pulse Test: pulse width \leq 300 μ s, duty cycle \leq 2%.
- 7. Switching characteristics are independent of operating junction temperatures.

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise specified)

Parameter	Symbol	Test Condition			Тур	Max	Unit
SWITCHING CHARACTERISTICS (N	ote 7)					•	
Turn-On Delay Time	t _{d(ON)}				9.0		
Rise Time	t _r	$V_{GS} = 4.5 \text{ V}, V_{D}$	_S = 15 V,		30		
Turn-Off Delay Time	t _{d(OFF)}	$I_D = 15 \text{ A}, R_G = 3.0 \Omega$			14		ns
Fall Time	t _f				7.0		
Turn-On Delay Time	t _{d(ON)}	V_{GS} = 10 V, V_{DS} = 15 V, I_{D} = 15 A, R_{G} = 3.0 Ω			6.0		ns
Rise Time	t _r				25		
Turn-Off Delay Time	t _{d(OFF)}				18		
Fall Time	t _f				4.0		
DRAIN-SOURCE DIODE CHARACT	ERISTICS						
Forward Diode Voltage	V_{SD}	$V_{GS} = 0 \text{ V},$ $I_{S} = 10 \text{ A}$ $T_{J} = 25^{\circ}\text{C}$ $T_{J} = 125^{\circ}\text{C}$			0.80	1.1	
					0.67		V
Reverse Recovery Time	t _{RR}	V_{GS} = 0 V, dIS/dt = 100 A/ μ s, I _S = 30 A			23.3		
Charge Time	t _a				12.7		ns
Discharge Time	t _b				10.6		
Reverse Recovery Charge	Q_{BB}	1 1			8.3		nC

^{6.} Pulse Test: pulse width \leq 300 μ s, duty cycle \leq 2%.
7. Switching characteristics are independent of operating junction temperatures.

TYPICAL CHARACTERISTICS

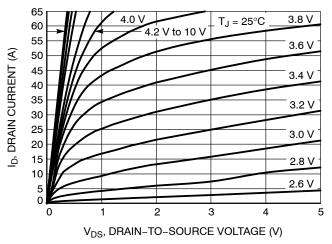


Figure 1. On-Region Characteristics

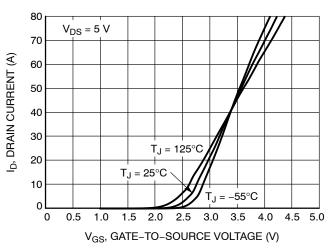


Figure 2. Transfer Characteristics

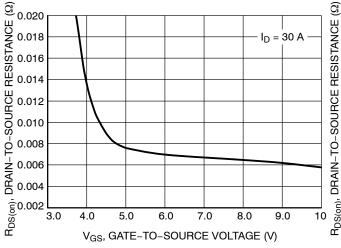


Figure 3. On-Resistance vs. V_{GS}

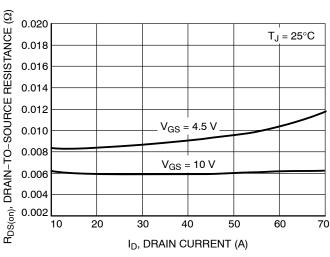


Figure 4. On-Resistance vs. Drain Current and Gate Voltage

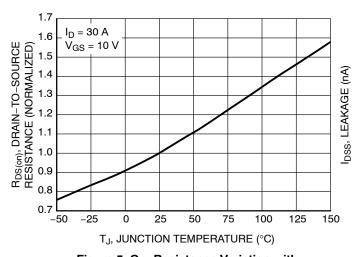


Figure 5. On–Resistance Variation with Temperature

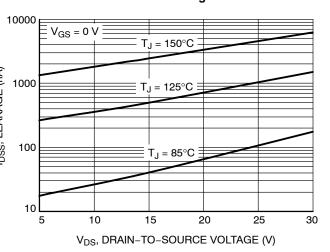


Figure 6. Drain-to-Source Leakage Current vs. Voltage

TYPICAL CHARACTERISTICS

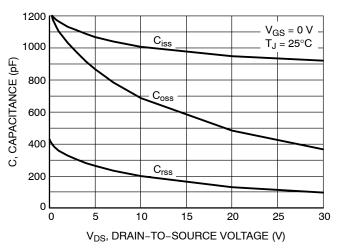


Figure 7. Capacitance Variation

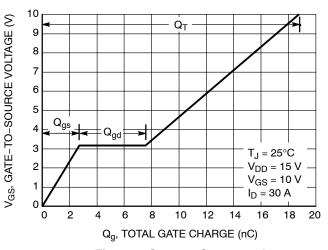


Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

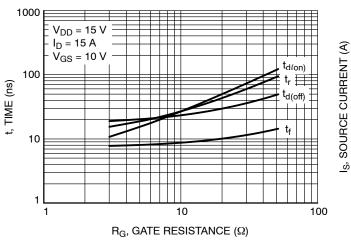


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

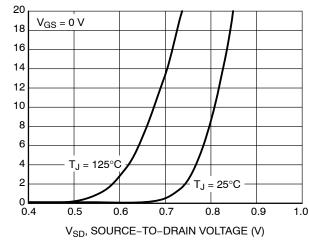


Figure 10. Diode Forward Voltage vs. Current

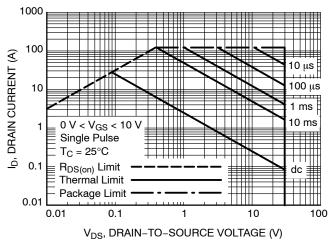


Figure 11. Maximum Rated Forward Biased Safe Operating Area

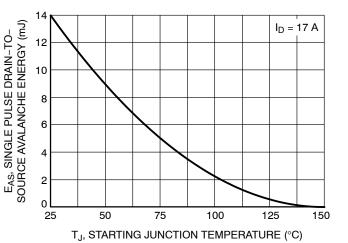


Figure 12. Maximum Avalanche Energy vs. Starting Junction Temperature

TYPICAL CHARACTERISTICS

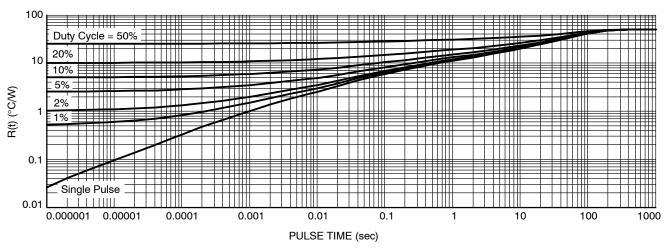
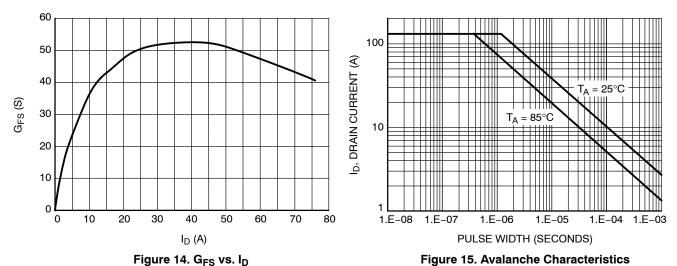


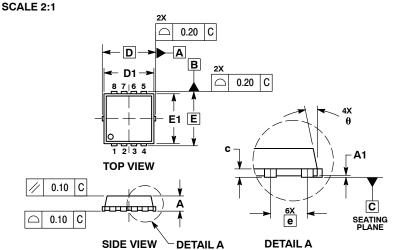
Figure 13. Thermal Response





WDFN8 3.3x3.3, 0.65P CASE 511AB ISSUE D

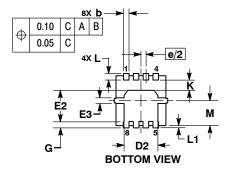
DATE 23 APR 2012



NOTES:

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
 CONTROLLING DIMENSION: MILLIMETERS.
 DIMENSION D1 AND E1 DO NOT INCLUDE MOLD FLASH
 PROTRUSIONS OR GATE BURRS.

	MILLIMETERS				INCHES		
DIM	MIN	NOM	MAX	MIN	NOM	MAX	
Α	0.70	0.75	0.80	0.028	0.030	0.031	
A1	0.00		0.05	0.000		0.002	
b	0.23	0.30	0.40	0.009	0.012	0.016	
С	0.15	0.20	0.25	0.006	0.008	0.010	
D		3.30 BSC		0	.130 BSC	;	
D1	2.95	3.05	3.15	0.116	0.120	0.124	
D2	1.98	2.11	2.24	0.078	0.083	0.088	
E		3.30 BSC		0.130 BSC			
E1	2.95	3.05	3.15	0.116	0.120	0.124	
E2	1.47	1.60	1.73	0.058	0.063	0.068	
E3	0.23	0.30	0.40	0.009	0.012	0.016	
е	0.65 BSC			(0.026 BS	0	
G	0.30	0.41	0.51	0.012	0.016	0.020	
K	0.65	0.80	0.95	0.026	0.032	0.037	
L	0.30	0.43	0.56	0.012	0.017	0.022	
L1	0.06	0.13	0.20	0.002	0.005	0.008	
М	1.40	1.50	1.60	0.055	0.059	0.063	
θ	0 °		12 °	0 °		12 °	



GENERIC MARKING DIAGRAM*

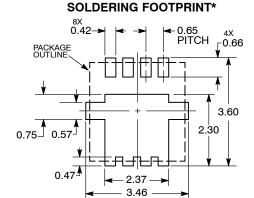


XXXXX = Specific Device Code = Assembly Location

= Year WW = Work Week = Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking.

Pb-Free indicator, "G" or microdot " ■", may or may not be present.



DIMENSION: MILLIMETERS

*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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DESCRIPTION:	WDFN8 3.3X3.3, 0.65P		PAGE 1 OF 1		

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